

**Search Notes**

Application/Control No.

10/695,791

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	214R, 231.13, 231.14, 231.18	9/15/2005	PL
356	614, 616	9/15/2005	PL
341	13	9/15/2005	PL
33	1PT	9/15/2005	PL
250	208.1	9/15/2005	PL
250	208.2	9/15/2005	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see attached)	3/23/2005	PL
Consulted w/ S. Allen	4/5/2005	PL
East (see attached)	4/6/2005	PL
East (see attached)	4/11/2005	PL
East (see attached)	4/12/2005	PL
East (see attached)	9/15/2005	PL